

FDH27N50

27A, 500V, 0.19 Ohm, N-Channel SMPS Power MOSFET

Applications

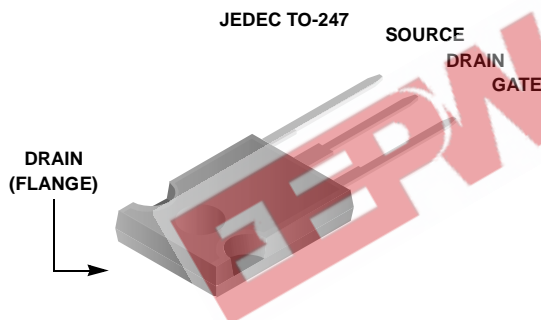
Switch Mode Power Supplies(SMPS), such as

- PFC Boost
- Two-Switch Forward Converter
- Single Switch Forward Converter
- Flyback Converter
- Buck Converter
- High Speed Switching

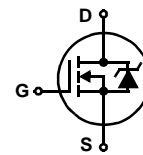
Features

- Low Gate Charge Qg results in Simple Drive Requirement
- Improved Gate, Avalanche and High Reapplied dv/dt Ruggedness
- Reduced $r_{DS(ON)}$
- Reduced Miller Capacitance and Low Input Capacitance
- Improved Switching Speed with Low EMI
- 175°C Rated Junction Temperature

Package



Symbol



Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Ratings | Units |
|----------------|--|-----------------------|---------------------|
| V_{DSS} | Drain to Source Voltage | 500 | V |
| V_{GS} | Gate to Source Voltage | ± 30 | V |
| I_D | Drain Current | | |
| | Continuous ($T_C = 25^\circ\text{C}$, $V_{GS} = 10\text{V}$) | 27 | A |
| | Continuous ($T_C = 100^\circ\text{C}$, $V_{GS} = 10\text{V}$) | 19 | A |
| | Pulsed (Note 1) | 108 | A |
| P_D | Power dissipation | 450 | W |
| | Derate above 25°C | 3 | W/ $^\circ\text{C}$ |
| T_J, T_{STG} | Operating and Storage Temperature | -55 to 175 | $^\circ\text{C}$ |
| | Soldering Temperature for 10 seconds | 300 (1.6mm from case) | $^\circ\text{C}$ |
| | Mounting Torque, 8-32 or M3 Screw | 10lbf*in (1.1N*m) | |

Thermal Characteristics

| | | | |
|-----------------|--|----------|---------------------------|
| $R_{\theta JC}$ | Thermal Resistance Junction to Case | 0.33 | $^\circ\text{C}/\text{W}$ |
| $R_{\theta CS}$ | Thermal Resistance Case to Sink, Flat, Greased Surface | 0.24 TYP | $^\circ\text{C}/\text{W}$ |
| $R_{\theta JA}$ | Thermal Resistance Junction to Ambient | 40 | $^\circ\text{C}/\text{W}$ |

Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|----------|---------|-----------|------------|----------|
| FDH27N50 | FDH27N50 | TO-247 | Tube | - | 30 |

Electrical Characteristics $T_c = 25^\circ\text{C}$ (unless otherwise noted)

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units | |
|------------------------------|-------------------------------------|---|---------------------------|------|-----------|---------------------------|---------------|
| Statics | | | | | | | |
| B_{VDSS} | Drain to Source Breakdown Voltage | $I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$ | 500 | - | - | V | |
| $\Delta B_{VDSS}/\Delta T_J$ | Breakdown Voltage Temp. Coefficient | Reference to 25°C $I_D = 1\text{mA}$ | - | 0.64 | - | $\text{V}/^\circ\text{C}$ | |
| $r_{DS(ON)}$ | Drain to Source On-Resistance | $V_{GS} = 10\text{V}$, $I_D = 13.5\text{A}$ | - | 0.17 | 0.19 | Ω | |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$ | 2.0 | 3.3 | 4.0 | V | |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = 500\text{V}$ | $T_C = 25^\circ\text{C}$ | - | - | 25 | μA |
| | | $V_{GS} = 0\text{V}$ | $T_C = 150^\circ\text{C}$ | - | - | 250 | |
| I_{GSS} | Gate to Source Leakage Current | $V_{GS} = \pm 30\text{V}$ | - | - | ± 100 | nA | |

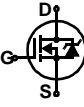
Dynamics

| | | | | | | |
|--------------|-------------------------------|--|----|------|----|----|
| g_{fs} | Forward Transconductance | $V_{DS} = 50\text{V}$, $I_D = 13.5\text{A}$ | 11 | - | - | S |
| $Q_{g(TOT)}$ | Total Gate Charge at 10V | $V_{GS} = 10\text{V}$ | - | 56 | 67 | nC |
| Q_{gs} | Gate to Source Gate Charge | $V_{DS} = 400\text{V}$ | - | 17 | 20 | nC |
| Q_{gd} | Gate to Drain "Miller" Charge | $I_D = 27\text{A}$ | - | 18 | 22 | nC |
| $t_{d(ON)}$ | Turn-On Delay Time | $V_{DD} = 250\text{V}$ | - | 14 | - | ns |
| t_r | Rise Time | $I_D = 27\text{A}$ | - | 54 | - | ns |
| $t_{d(OFF)}$ | Turn-Off Delay Time | $R_G = 4.3\Omega$ | - | 47 | - | ns |
| t_f | Fall Time | $R_D = 9.3\Omega$ | - | 54 | - | ns |
| C_{ISS} | Input Capacitance | $V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$ | - | 3550 | - | pF |
| C_{OSS} | Output Capacitance | $f = 1\text{MHz}$ | - | 409 | - | pF |
| C_{RSS} | Reverse Transfer Capacitance | | - | 22 | - | pF |

Avalanche Characteristics

| | | | | | | |
|----------|--|--|------|---|----|----|
| E_{AS} | Single Pulse Avalanche Energy (Note 2) | | 2552 | - | - | mJ |
| I_{AR} | Avalanche Current | | - | - | 27 | A |

Drain-Source Diode Characteristics

| | | | | | | |
|----------|---|--|---|------|-----|---------------|
| I_S | Continuous Source Current (Body Diode) | MOSFET symbol showing the integral reverse p-n junction diode. | - | - | 27 | A |
| I_{SM} | Pulsed Source Current (Note 1) (Body Diode) |  | - | - | 108 | A |
| V_{SD} | Source to Drain Diode Voltage | $I_{SD} = 27\text{A}$ | - | 0.89 | 1.2 | V |
| t_{rr} | Reverse Recovery Time | $I_{SD} = 27\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$ | - | 563 | 714 | ns |
| Q_{RR} | Reverse Recovered Charge | $I_{SD} = 27\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$ | - | 9.2 | 14 | μC |

Notes:

- 1: Repetitive rating; pulse width limited by maximum junction temperature
- 2: Starting $T_J = 25^\circ\text{C}$, $L = 7\text{mH}$, $I_{AS} = 27\text{A}$

Typical Characteristics

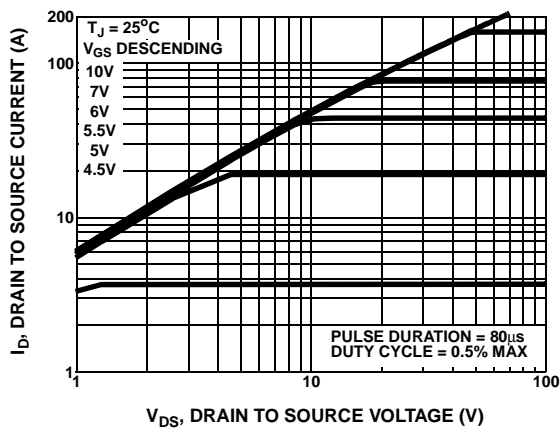


Figure 1. Output Characteristics

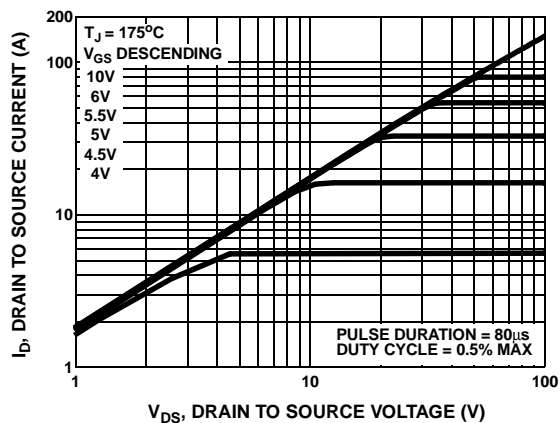


Figure 2. Output Characteristics

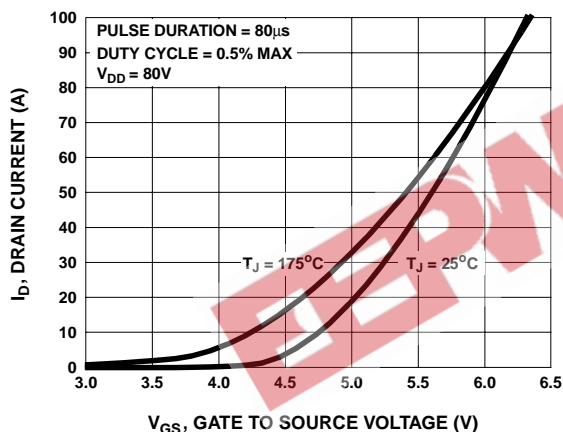


Figure 3. Transfer Characteristics

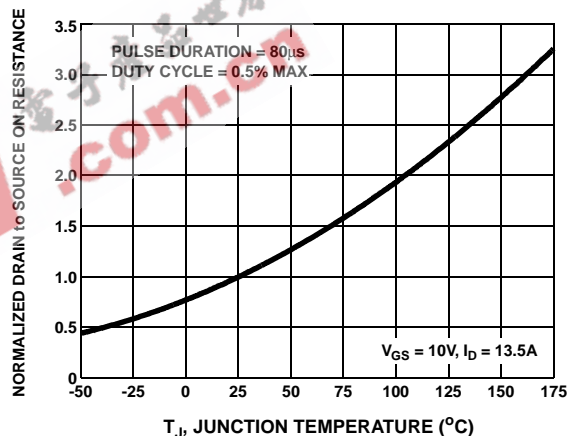


Figure 4. Normalized Drain To Source On Resistance vs Junction Temperature

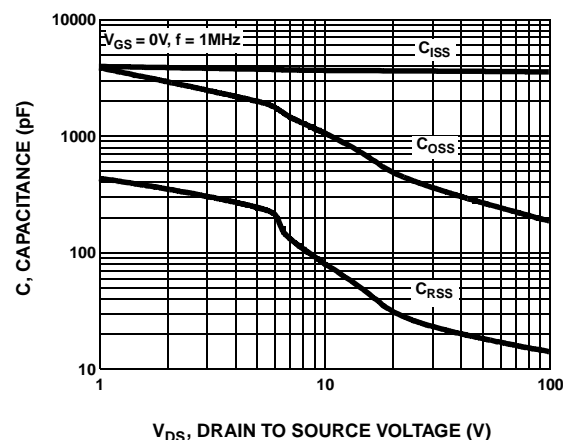


Figure 5. Capacitance vs Drain To Source Voltage

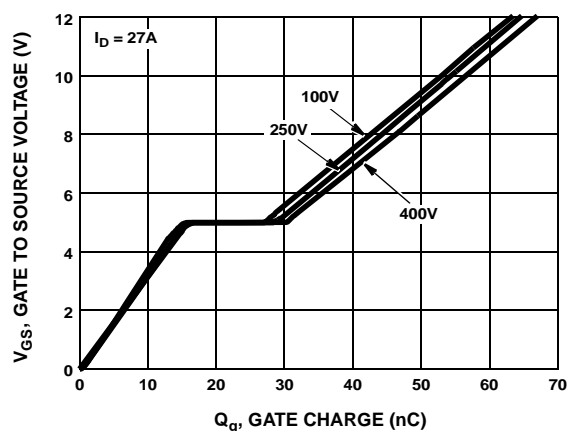


Figure 6. Gate Charge Waveforms For Constant Gate Current

Typical Characteristics (Continued)

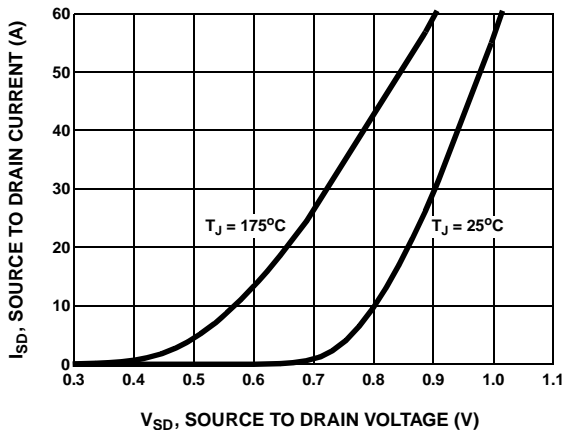


Figure 7. Body Diode Forward Voltage vs Body Diode Current

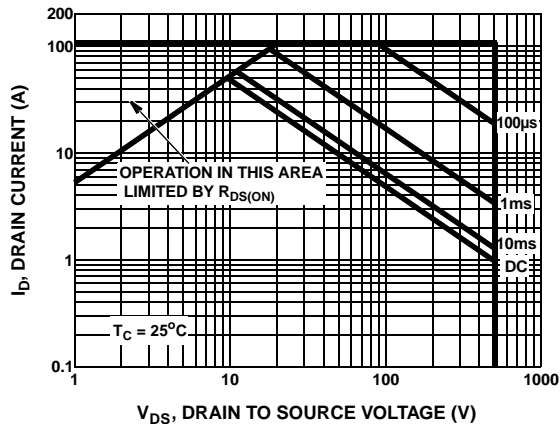


Figure 8. Maximum Safe Operating Area

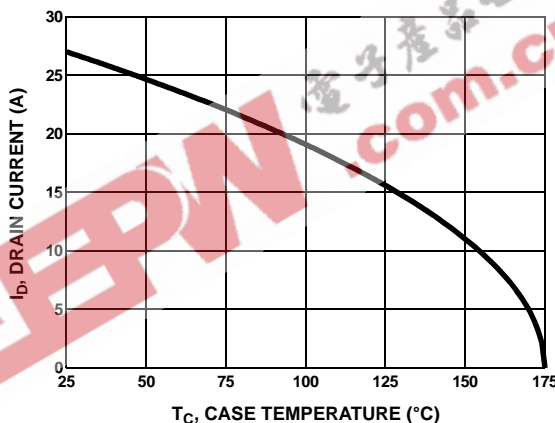


Figure 9. Maximum Drain Current vs Case Temperature

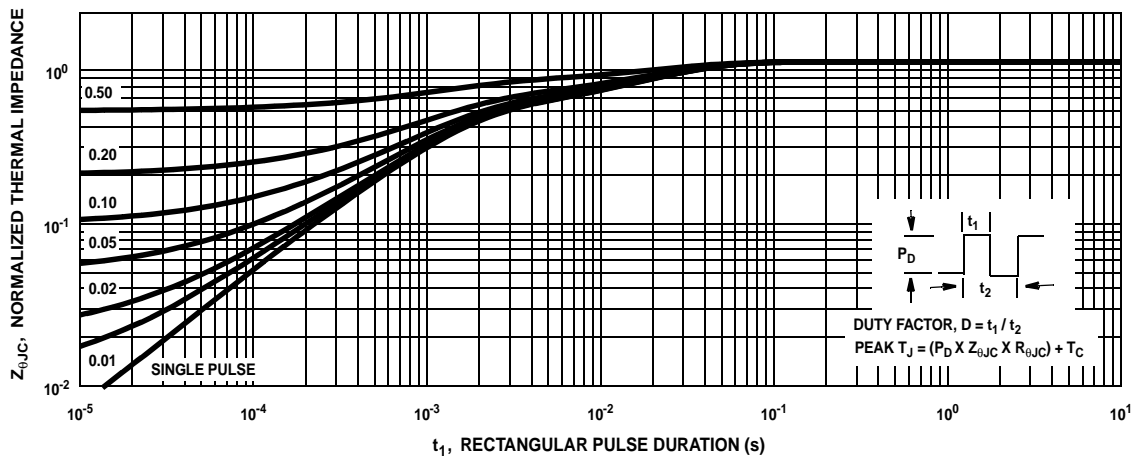


Figure 10. Normalized Maximum Transient Thermal Impedance

Test Circuits and Waveforms

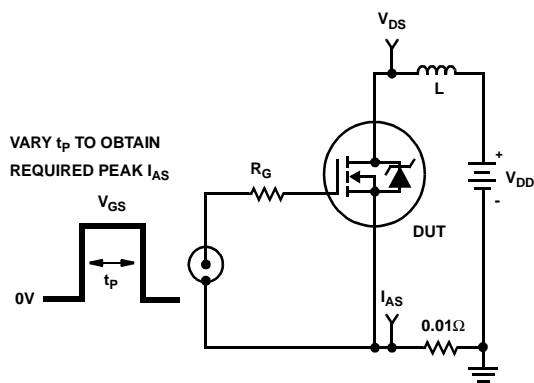


Figure 11. Unclamped Energy Test Circuit

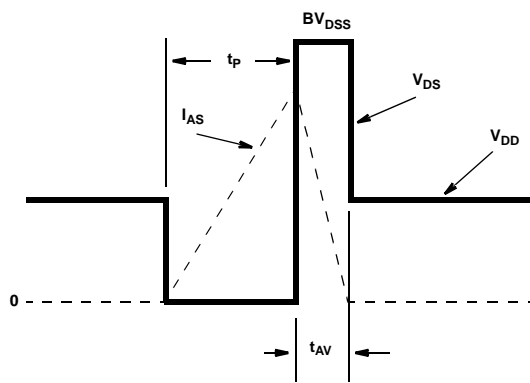


Figure 12. Unclamped Energy Waveforms

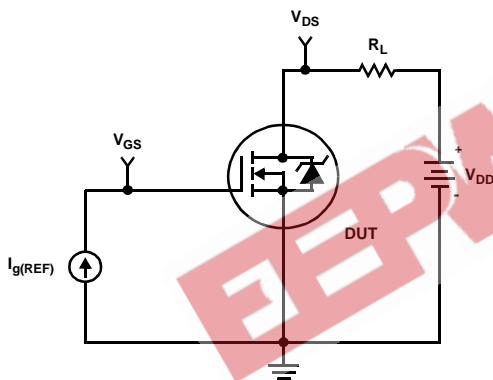


Figure 13. Gate Charge Test Circuit

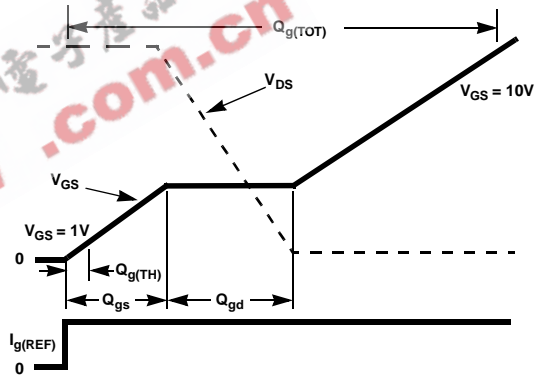


Figure 14. Gate Charge Waveforms

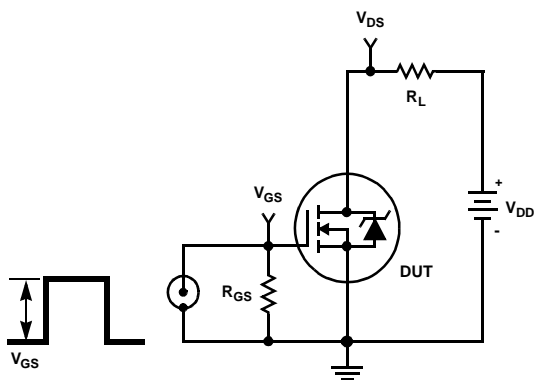


Figure 15. Switching Time Test Circuit

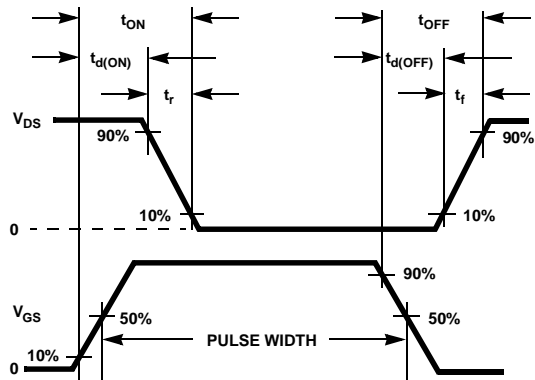


Figure 16. Switching Time Waveform

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